January 2001

# Si4463DY

SEMICONDUCTOR

# P-Channel 2.5V Specified PowerTrench<sup>®</sup> MOSFET

### **General Description**

This P-Channel 2.5V specified MOSFET uses a rugged gate PowerTrench process. It has been optimized for power management applications with a wide range of gate drive voltage (2.5V - 12V).

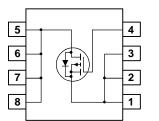
## Applications

- Power management
- Load switch
- Battery protection

# D D D C SO-8 S S G



- -11.5 A, -20 V.  $R_{DS(ON)}$  = 12 m $\Omega$  @  $V_{GS}$  = -4.5 V  $R_{DS(ON)}$  = 17.5 m $\Omega$  @  $V_{GS}$  = -2.5 V
- Fast switching speed.
- High performance trench technology for extremely low  $R_{\text{DS}(\text{ON})}$
- High power and current handling capability



# Absolute Maximum Ratings T<sub>A</sub>=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V <sub>DSS</sub>	Drain-Source Voltage		-20	V
V <sub>GSS</sub>	Gate-Source Voltage		± 12	V
I <sub>D</sub>	Drain Current – Continuous	(Note 1a)	-11.5	А
	- Pulsed		-50	
P <sub>D</sub>	Power Dissipation for Single Operation	(Note 1a)	2.5	W
		(Note 1b)	1.2	
		(Note 1c)	1.0	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range		-55 to +150	°C

# Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	50	°C/W
R <sub>eJC</sub>	Thermal Resistance, Junction-to-Case	(Note 1)	25	°C/W

# Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity	
4463	Si4463DY	13"	12mm	2500 units	

©2001 Fairchild Semiconductor International

Si4463DY

eristics ain–Source Breakdown Voltage eakdown Voltage Temperature efficient ro Gate Voltage Drain Current	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$ $I_D = -250 \mu\text{A}, \text{ Referenced to } 25^\circ\text{C}$	-20			V
ain–Source Breakdown Voltage eakdown Voltage Temperature efficient ro Gate Voltage Drain Current		-20			V
efficient ro Gate Voltage Drain Current	$I_D = -250 \ \mu\text{A}$ , Referenced to $25^{\circ}\text{C}$				
-			-12		mV/°C
	$V_{\text{DS}} = -16 \text{ V},  V_{\text{GS}} = 0 \text{ V}$			-1	μA
te–Body Leakage, Forward	$V_{GS} = 12 \text{ V}, \qquad V_{DS} = 0 \text{ V}$			100	nA
te-Body Leakage, Reverse	$V_{GS} = -12 \text{ V},  V_{DS} = 0 \text{ V}$			-100	nA
eristics (Note 2)					
te Threshold Voltage	$V_{DS} = V_{GS}, I_D = -250 \ \mu A$	-0.6	-0.8	-1.5	V
te Threshold Voltage mperature Coefficient	$I_D = -250 \mu\text{A}$ , Referenced to 25°C		3		mV/°C
atic Drain–Source –Resistance	$ \begin{array}{ll} V_{GS} = -4.5 \ V, & I_D = -11.5 \ A \\ V_{GS} = -2.5 \ V, & I_D = -9.5 \ A \\ V_{GS} = -4.5 \ V, \ I_D = -11.5 A, \ T_J = 125^\circ C \end{array} $		10 14 13	12 17.5 18	mΩ
-State Drain Current	$V_{GS} = -4.5 \text{ V}, \qquad V_{DS} = -5 \text{ V}$	-50			А
rward Transconductance	$V_{DS} = -10 \text{ V}, \qquad I_D = -10 \text{ A}$		49		S
naracteristics					
ut Capacitance	$V_{DS} = -10 \text{ V},  V_{GS} = 0 \text{ V},$		4481		pF
tput Capacitance	f = 1.0 MHz		1532		pF
verse Transfer Capacitance			540		pF
haracteristics (Note 2)					
rn–On Delay Time	$V_{DD} = -5 V$ , $I_D = -1 A$ ,		15	30	ns
rn–On Rise Time	$V_{GS} = -4.5 \text{ V}, \qquad R_{GEN} = 6 \Omega$		15	30	ns
rn–Off Delay Time			120	240	ns
rn–Off Fall Time			60	120	ns
tal Gate Charge	$V_{DS} = -10 \text{ V}, \qquad I_D = -11.5 \text{ A},$		41	60	nC
te-Source Charge	$V_{GS} = -4.5 V$		6.4		nC
te–Drain Charge			11.8		nC
ce Diode Characteristics	and Maximum Ratings				
				-2.1	Α
ain–Source Diode Forward Itage	$V_{GS} = 0 V$ , $I_S = -1.5 A$ (Note 2)		-0.65	-1.2	V
	te Threshold Voltage mperature Coefficient tic Drain–Source –Resistance –State Drain Current ward Transconductance maracteristics ut Capacitance tput Capacitance tput Capacitance verse Transfer Capacitance Characteristics (Note 2) m–On Delay Time m–On Rise Time m–Off Delay Time m–Off Fall Time al Gate Charge te–Source Charge te–Drain Charge ce Diode Characteristics ximum Continuous Drain–Source ain–Source Diode Forward tage	te Threshold Voltage mperature Coefficient $V_{DS} = V_{GS}$ , $I_D = -250 \ \mu A$ te Threshold Voltage mperature Coefficient $I_D = -250 \ \mu A$ , Referenced to 25°C-Resistance $V_{GS} = -4.5 \ V$ , $I_D = -11.5 \ A$ -Resistance $V_{GS} = -4.5 \ V$ , $I_D = -9.5 \ A$ V_{GS} = -4.5 \ V, $I_D = -11.5 \ A$ , $T_J = 125°C$ -State Drain Current $V_{GS} = -4.5 \ V$ , $V_{DS} = -5 \ V$ ward Transconductance $V_{DS} = -10 \ V$ , $I_D = -10 \ A$ maracteristicsut Capacitanceut Capacitance $V_{DS} = -10 \ V$ , $V_{GS} = 0 \ V$ , f = 1.0 MHzverse Transfer Capacitance $V_{DS} = -5 \ V$ , $I_D = -1 \ A$ , $V_{GS} = -4.5 \ V$ , $R_{GEN} = 6 \ \Omega$ m-On Delay Time m-Off Delay Time $V_{DS} = -10 \ V$ , $I_D = -11.5 \ A$ , $V_{GS} = -4.5 \ V$ , $R_{GEN} = 6 \ \Omega$ m-Off Fall Time al Gate Charge te-Drain Charge $V_{DS} = -10 \ V$ , $I_D = -11.5 \ A$ , $V_{GS} = -4.5 \ V$ ce Diode Characteristics and Maximum Ratings ximum Continuous Drain–Source Diode Forward Current ain–Source Diode Forward tage $V_{GS} = 0 \ V$ , $I_S = -1.5 \ A$ (Note 2)	te Threshold Voltage te Threshold Voltage mperature Coefficient $V_{DS} = V_{GS}$ , $I_D = -250 \ \mu A$ $-0.6$ Ib = Threshold Voltage mperature Coefficient $I_D = -250 \ \mu A$ , Referenced to $25^{\circ}C$ $I_D = -250 \ \mu A$ , Referenced to $25^{\circ}C$ Threshold Voltage mperature Coefficient $V_{GS} = -4.5 \ V$ , $I_D = -11.5 \ A$ $V_{GS} = -2.5 \ V$ , $I_D = -9.5 \ A$ -State Drain Current $V_{GS} = -4.5 \ V$ , $I_D = -11.5 \ A$ , $T_J = 125^{\circ}C$ -50-State Drain Current $V_{GS} = -4.5 \ V$ , $V_{DS} = -5 \ V$ -50ward Transconductance $V_{DS} = -10 \ V$ , $I_D = -10 \ A$ -0.6 <b>haracteristics</b> ut Capacitance $V_{DS} = -10 \ V$ , $I_D = -10 \ A$ -0.6 <b>haracteristics</b> (Note 2) $V_{DS} = -10 \ V$ , $I_D = -10 \ A$ -0.6m-On Delay Time m-On Rise Time $V_{DD} = -5 \ V$ , $I_D = -1 \ A$ , $V_{GS} = -4.5 \ V$ , $R_{GEN} = 6 \ \Omega$ -0.6m-Off Fall Time al Gate Charge te-Drain Charge $V_{DS} = -10 \ V$ , $I_D = -11.5 \ A$ , $V_{GS} = -4.5 \ V$ -0.6 <b>ce Diode Characteristics and Maximum Ratings</b> ximum Continuous Drain-Source Diode Forward Current tage-0.6 (Note 2)e junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined a	te Threshold Voltage $V_{DS} = V_{GS}$ , $I_D = -250 \ \mu A$ $-0.6$ $-0.8$ te Threshold Voltage $I_D = -250 \ \mu A$ , Referenced to $25^{\circ}C$ 3 tic Drain–Source $V_{GS} = -4.5 \ V$ , $I_D = -11.5 \ A$ 10 -Resistance $V_{GS} = -4.5 \ V$ , $I_D = -9.5 \ A$ 14 $V_{GS} = -4.5 \ V$ , $I_D = -9.5 \ A$ 14 $V_{GS} = -4.5 \ V$ , $I_D = -9.5 \ A$ 14 $V_{GS} = -4.5 \ V$ , $I_D = -10 \ A$ 49 haracteristics ut Capacitance $V_{DS} = -10 \ V$ , $I_D = -10 \ A$ 49 haracteristics ut Capacitance $V_{DS} = -10 \ V$ , $V_{GS} = 0 \ V$ , $\frac{4481}{1532}$ verse Transfer Capacitance $f = 1.0 \ MHz$ $1532$ verse Transfer Capacitance $V_{DD} = -5 \ V$ , $I_D = -1 \ A$ , $\frac{15}{150}$ m-On Delay Time $V_{GS} = -4.5 \ V$ , $R_{GEN} = 6 \ \Omega$ $15$ m-Off Delay Time $V_{GS} = -4.5 \ V$ , $R_{GEN} = 6 \ \Omega$ $15$ m-Off Fall Time $1200$ m-Off Fall Time $1200$ m-Off Fall Time $1200$ m-Off Fall Time $1200$ m-Off Fall Time $11.8 \ K_{GS} = -4.5 \ V$ $I_D = -11.5 \ A$ , $411 \ V_{GS} = -4.5 \ V$ $I_D = -11.5 \ A$ , $411 \ V_{GS} = -4.5 \ V$ $I_D = -11.5 \ A$ , $411 \ V_{GS} = -4.5 \ V$ $I_D = -11.5 \ A$ , $411 \ V_{GS} = -4.5 \ V$ $I_D = -11.5 \ A$ , $411 \ V_{GS} = -4.5 \ V$ $I_D = -11.5 \ A$ , $411 \ V_{GS} = -4.5 \ V$ $I_D = -11.5 \ A$ , $411 \ V_{GS} = -4.5 \ V$ $I_D = -11.5 \ A$ , $411 \ V_{GS} = -4.5 \ V$ $I_D = -11.5 \ A$ , $V_{GS} = -4.5 \ V$ $I_D = -11.5 \ A$ , $I_D = -100 \ A$ , $I$	te Threshold Voltage mperature Coefficient $V_{DS} = V_{GS}$ , $I_D = -250 \ \mu$ A $-0.6$ $-0.8$ $-1.5$ te Threshold Voltage mperature Coefficient $I_D = -250 \ \mu$ A, Referenced to $25^{\circ}$ C31012tic Drain–Source –Resistance $V_{GS} = -4.5 \ V$ , $I_D = -11.5 \ A$ 1012Resistance $V_{GS} = -4.5 \ V$ , $I_D = -9.5 \ A$ 1417.5State Drain Current $V_{GS} = -4.5 \ V$ , $V_{DS} = -5 \ V$ $-50$ 13State Drain Current $V_{GS} = -4.5 \ V$ , $V_{DS} = -5 \ V$ $-50$ $4481$ maracteristics $V_{DS} = -10 \ V$ , $I_D = -10 \ A$ $49$ maracteristics $V_{DS} = -10 \ V$ , $I_D = -10 \ A$ $49$ maracteristics $V_{DS} = -10 \ V$ , $I_D = -10 \ A$ $49$ monon Rise Time $V_{DS} = -10 \ V$ , $I_D = -1 \ A$ , $I_D = -10 \ A$ $1532$ m-On Delay Time $V_{DS} = -5 \ V$ , $I_D = -1 \ A$ , $I_D = -1 \ A$ , $I_D = -10 \ A$ $160 \ 120$ m-Off Fall Time $V_{OS} = -4.5 \ V$ , $R_{GEN} = 6 \ \Omega$ $15 \ 30$ m-Off Fall Time $I_D = -10 \ V$ , $I_D = -11.5 \ A$ , $V_{CS} = -4.5 \ V$ $6.4 \ 11.8 \ Ce Diode Characteristics and Maximum Ratings$ time Continuous Drain–Source Diode Forward Current $-2.1 \ 11.8 \ Contentioned Forward Current$ $-2.1 \ 11.8 \ -2.1 \ 11.8$

Scale 1 : 1 on letter size paper

2. Pulse Test: Pulse Width < 300 $\mu$ s, Duty Cycle < 2.0%

#### TRADEMARKS

The following are registered and unregistered trademarks Fairchild Semiconductor owns or is authorized to use and is not intended to be an exhaustive list of all such trademarks.

ACEx™ Bottomless™ CoolFET™ CROSSVOLT™ DOME™ E<sup>2</sup>CMOS<sup>™</sup> EnSigna™ FACT™ FACT Quiet Series<sup>™</sup> FAST<sup>®</sup>

FASTr™ GlobalOptoisolator™ GTO™ HiSeC™ **ISOPLANAR™** MICROWIRE™ OPTOLOGIC™ **OPTOPLANAR™** PACMAN™ POP™

PowerTrench<sup>®</sup> QFET™ QS™ QT Optoelectronics<sup>™</sup> Quiet Series<sup>™</sup> SILENT SWITCHER® SMART START™ SuperSOT<sup>™</sup>-3 SuperSOT<sup>™</sup>-6 SuperSOT<sup>™</sup>-8

SyncFET™ TinyLogic™ UHC™ VCX™

#### DISCLAIMER

FAIRCHILD SEMICONDUCTOR RESERVES THE RIGHT TO MAKE CHANGES WITHOUT FURTHER NOTICE TO ANY PRODUCTS HEREIN TO IMPROVE RELIABILITY, FUNCTION OR DESIGN. FAIRCHILD DOES NOT ASSUME ANY LIABILITY ARISING OUT OF THE APPLICATION OR USE OF ANY PRODUCT OR CIRCUIT DESCRIBED HEREIN; NEITHER DOES IT CONVEY ANY LICENSE UNDER ITS PATENT RIGHTS, NOR THE RIGHTS OF OTHERS.

#### LIFE SUPPORT POLICY

FAIRCHILD'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF FAIRCHILD SEMICONDUCTOR CORPORATION. As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, or (c) whose failure to perform when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in significant injury to the user.

2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

#### PRODUCT STATUS DEFINITIONS

**Definition of Terms** 

Datasheet Identification	Product Status	Definition
Advance Information	Formative or In Design	This datasheet contains the design specifications for product development. Specifications may change in any manner without notice.
Preliminary	First Production	This datasheet contains preliminary data, and supplementary data will be published at a later date. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
No Identification Needed	Full Production	This datasheet contains final specifications. Fairchild Semiconductor reserves the right to make changes at any time without notice in order to improve design.
Obsolete	Not In Production	This datasheet contains specifications on a product that has been discontinued by Fairchild semiconductor. The datasheet is printed for reference information only.
	1	Rev G